

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Examination HEUER, JOERG	
	09/784,352	Examiner	Art Unit Chongshan Chen
		2172	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-6,345,269	02-2002	Kappenberger et al.	707/3
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	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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